

# SN5470, SN7470 AND-GATED J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

SDLS116 – DECEMBER 1983 – REVISED MARCH 1988

- Package Options Include Plastic and Ceramic DIPs and Ceramic Flat Packages
- Dependable Texas Instruments Quality and Reliability

## description

These monolithic, edge-triggered J-K flip-flops feature gated inputs, direct clear and preset inputs, and complementary Q and  $\bar{Q}$  outputs. Input information is transferred to the outputs on the positive edge of the clock pulse.

Direct-coupled clock triggering occurs at a specific voltage level of the clock pulse, and after the clock input threshold voltage has been passed, the gated inputs are locked out.

These flip-flops are ideally suited for medium-to-high-speed applications and can result in a significant saving in system power dissipation and package count where input gating is required.

The SN5470 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN7470 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

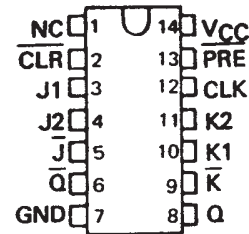
FUNCTION TABLE

INPUTS					OUTPUTS	
PRE	CLR	CLK	J	K	Q	$\bar{Q}$
L	H	L	X	X	H	L
H	L	L	X	X	L	H
L	L	X	X	X	L <sup>†</sup>	L <sup>†</sup>
H	H	↑	L	L	Q <sub>0</sub>	Q <sub>0</sub>
H	H	↑	H	L	H	L
H	H	↑	L	H	L	H
H	H	↑	H	H	TOGGLE	
H	H	L	X	X	Q <sub>0</sub>	Q <sub>0</sub>

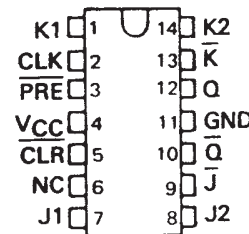
If inputs J and K are not used, they must be grounded. Preset or clear function can occur only when the clock input is low.

<sup>†</sup>This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

SN5470 ... J PACKAGE  
SN7470 ... N PACKAGE  
(TOP VIEW)

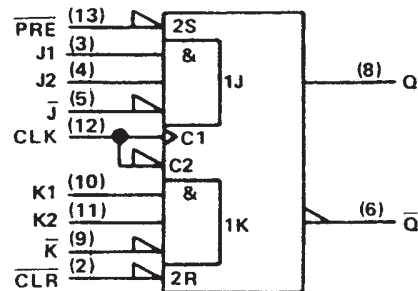


SN5470 ... W PACKAGE  
(TOP VIEW)



NC - No internal connection

## logic symbol†



<sup>†</sup>This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for J and N packages only.

## positive logic

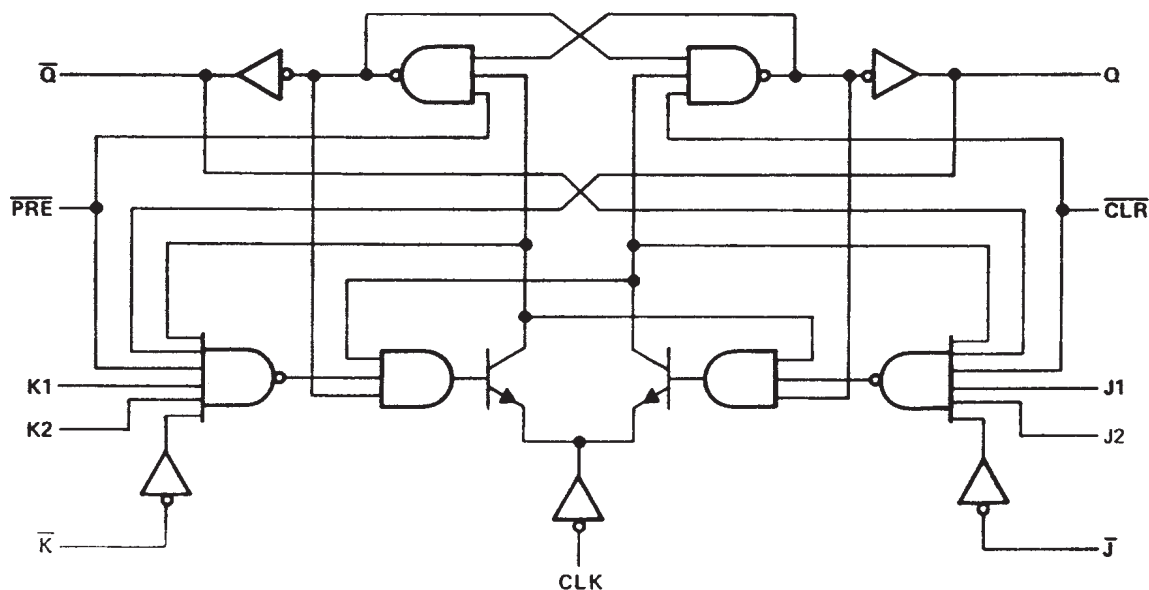
$$J = J1 \cdot J2 \cdot \bar{J}$$

$$K = K1 \cdot K2 \cdot \bar{K}$$

# SN5470, SN7470 AND-GATED J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

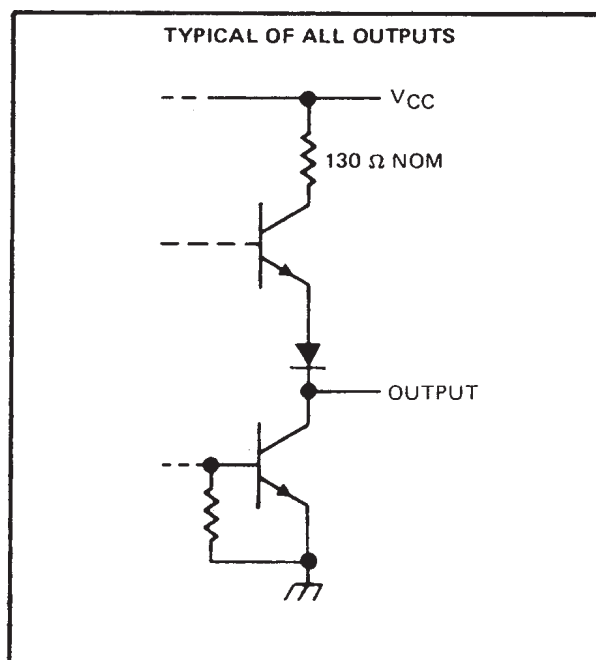
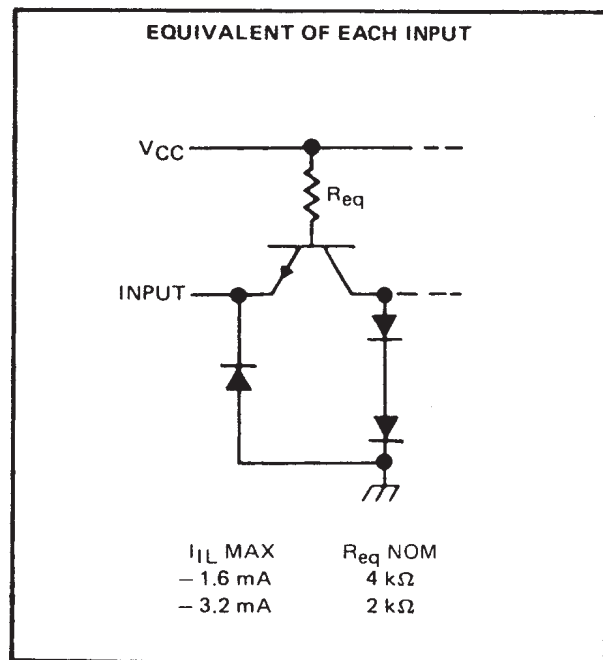
SDLS116 – DECEMBER 1983 – REVISED MARCH 1988

## logic diagram (positive logic)



'70-GATED J-K WITH CLEAR AND PRESET

## schematics of input and outputs



# SN5470, SN7470

## AND-GATED J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

SDLS116 – DECEMBER 1983 – REVISED MARCH 1988

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, $V_{CC}$ (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature: SN5470	– 55°C to 125°C
SN7470	0°C to 70°C
Storage temperature range	– 65°C to 150°C

NOTE 1: All voltage values are with respect to network ground terminal.

recommended operating conditions

			SN5470			SN7470			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
V <sub>IH</sub>	High-level input voltage		2			2			V
V <sub>IL</sub>	Low-level input voltage				0.8			0.8	V
I <sub>OH</sub>	High-level output current				− 0.4			− 0.4	mA
I <sub>OL</sub>	Low-level output current				16			16	mA
t <sub>w</sub>	Pulse duration	CLK high	20			20			ns
		CLK low	30			30			
		PRE or CLR low	25			25			
t <sub>su</sub>	Setup time before CLK ↑		20			20			ns
t <sub>h</sub>	Hold time-Data after CLK ↑		5			5			ns
T <sub>A</sub>	Operating free-air temperature		− 55			125			°C

†‡ The arrow indicates the edge of the clock pulse used for reference:  $\uparrow$  for the rising edge,  $\downarrow$  for the falling edge.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		SN5470			SN7470			UNIT
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	
$V_{IK}$		$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$		– 1.5			– 1.5			V
$V_{OH}$		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -0.4 \text{ mA}$		2.4	3.4		2.4	3.4		V
$V_{OL}$		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$			0.2	0.4		0.2	0.4	V
$I_I$		$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$				1			1	mA
$I_{IH}$	$\overline{PRE}$ or $\overline{CLR}$	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$				80			80	$\mu\text{A}$
	All other					40			40	
$I_{IL}$	$\overline{PRE}$ or $\overline{CLR}\dagger$	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$				– 3.2			– 3.2	mA
	All other					– 1.6			– 1.6	
$I_{OS}\S$		$V_{CC} = \text{MAX}$		– 20		– 57	– 18		– 57	mA
$I_{CC}$		$V_{CC} = \text{MAX},$ See Note 2			13	26		13	26	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

§Not more than one output should be shorted at a time.

†Clear is tested with preset high and preset is tested with clear high.

NOTE 2: With all outputs open,  $I_{CC}$  is measured with the Q and  $\overline{Q}$  outputs high in turn. At the time of measurement, the clock input is at 4.5 V.

# SN5470, SN7470

## AND-GATED J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

SDLS116 – DECEMBER 1983 – REVISED MARCH 1988

switching characteristics,  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$  (see note 3)

PARAMETER†	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f <sub>max</sub>			R <sub>L</sub> = 400 Ω,                      C <sub>L</sub> = 15 pF	20	35		MHz
t <sub>PLH</sub>	PRE or CLR	Q or Q̄				50	ns
t <sub>PHL</sub>						50	ns
t <sub>PLH</sub>	CLK	Q or Q̄			27	50	ns
t <sub>PHL</sub>					18	50	ns

† $f_{\max}$  = maximum clock frequency;  $t_{PLH}$  = propagation delay time, low-to-high level output;

$t_{PHL}$  = propagation delay time, high-to-low level output.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

## **IMPORTANT NOTICE**

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.